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Inventor: **Denise M. Eppich et al.**

Title: **Methods of Forming Transistor Devices and Capacitor Constructions**

Assignee: **Micron Technology, Inc.**

Serial No.: **10/757,253**

Filed: **January 13, 2004 [RCE Filed Herewith]**

**INFORMATION DISCLOSURE STATEMENT**

**PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98**

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. No admission is made regarding whether the listed references are prior art.

Citation of these references is respectfully requested.

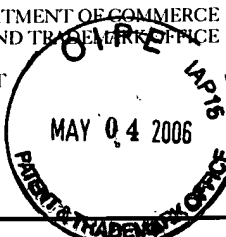
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Respectfully submitted,

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2467SERIAL NO.  
10/757,253LIST OF ART CITED BY APPLICANT  
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Jan. 13, 2004 [RCE filed herewith]GROUP  
2823

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,740,901 B2	05/04	Miki et al.			
	AB	6,600,212 B2	07/03	Takayanagi et al.			
	AC	2002/0014649 A1	02/02	Kunikiyo			
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	AK						
	AL						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AO		
	AP		
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